



Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10622294	CHOWN, DAVID
	Examiner Liu, Li	Art Unit 2613

Notes	Date	Examiner
EAST		
USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	08/03/2006	LL
Google	08/03/20063	LL
IEEE	08/03/2006	LL
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<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10622294</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>CHOWN, DAVID</p>
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Class	SubClass	Date	Examiner
372	102	08/03/2006	LL
398	152, 129, 58, 122, 125	08/03/2006	LL
385	12, 93, 49	08/03/2006	LL
250	25	08/03/2006	LL
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